



## 17. TEST PHOTOGRAPHS

See following Attached Pages for setup photographs.

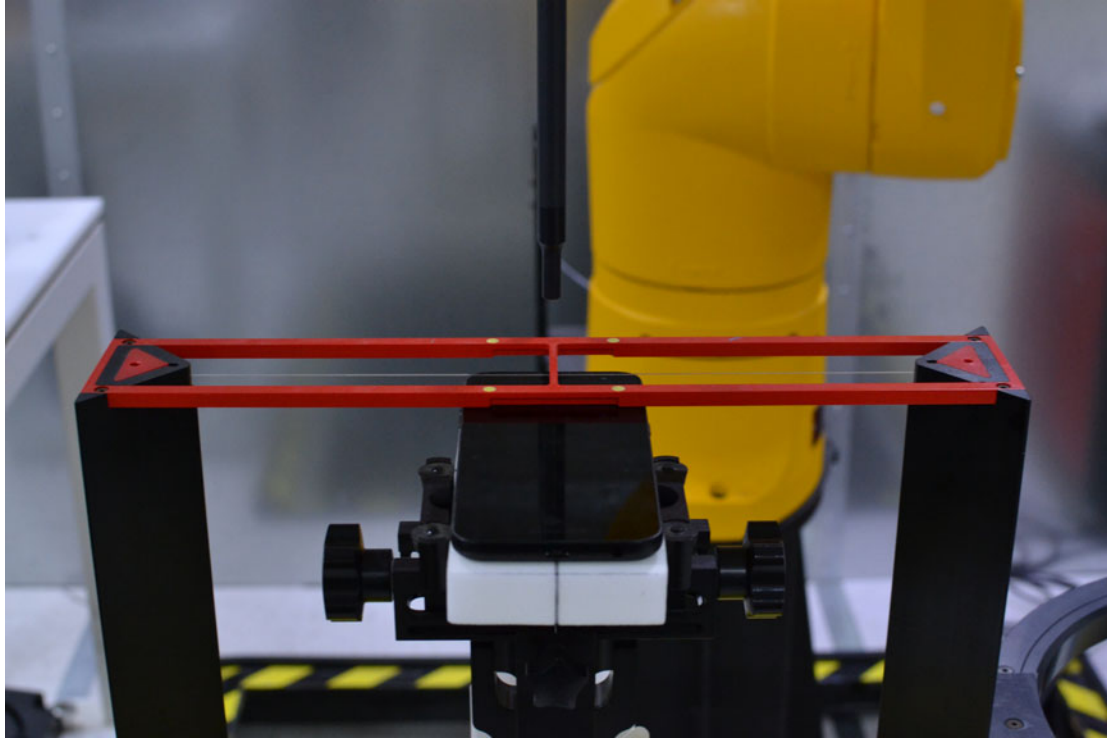
<b>FCC ID:</b> A3LSMJ260AZ	 <b>PCTEST</b> ENGINEERING LABORATORY, INC.	<b>HAC (RF EMISSIONS) TEST REPORT</b>		<b>Approved by:</b> Quality Manager
<b>Filename:</b> 1M1809210180-10-R1.A3L	<b>Test Dates:</b> 10/08/2018 - 10/11/2018	<b>DUT Type:</b> Portable Handset	Page 66 of 68	

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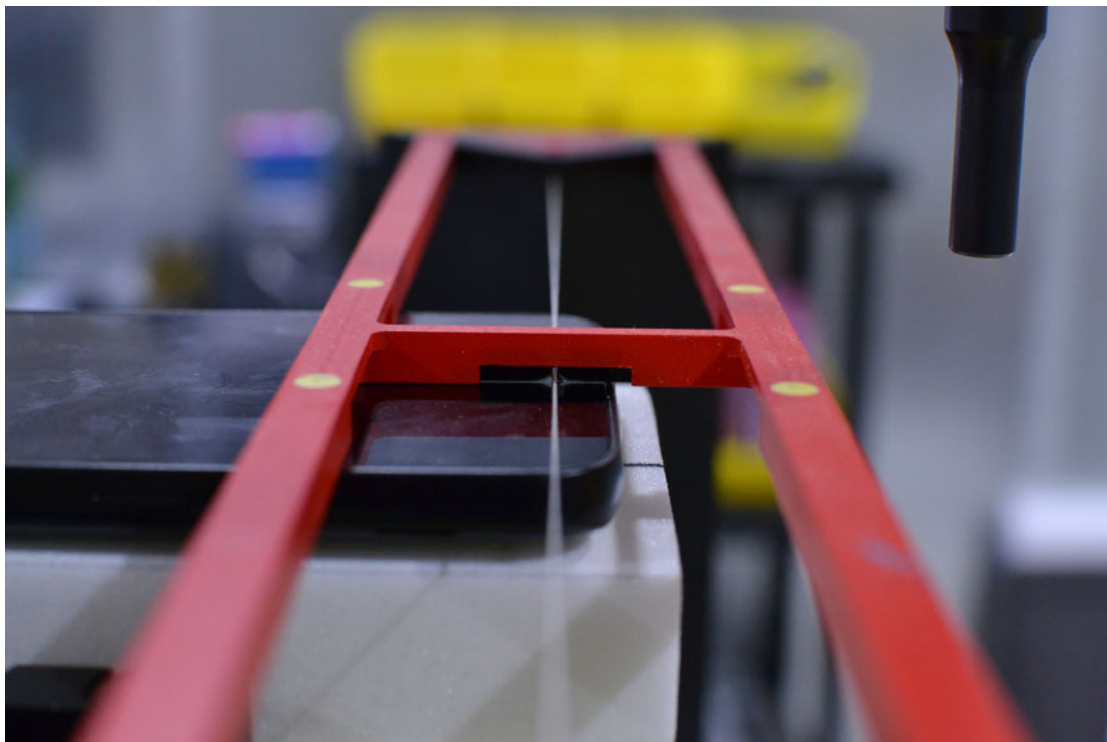
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**Figure 17-1**  
**Ear Reference Point HAC Phantom Alignment**



**Figure 17-2**  
**HAC Phantom Plane Alignment**

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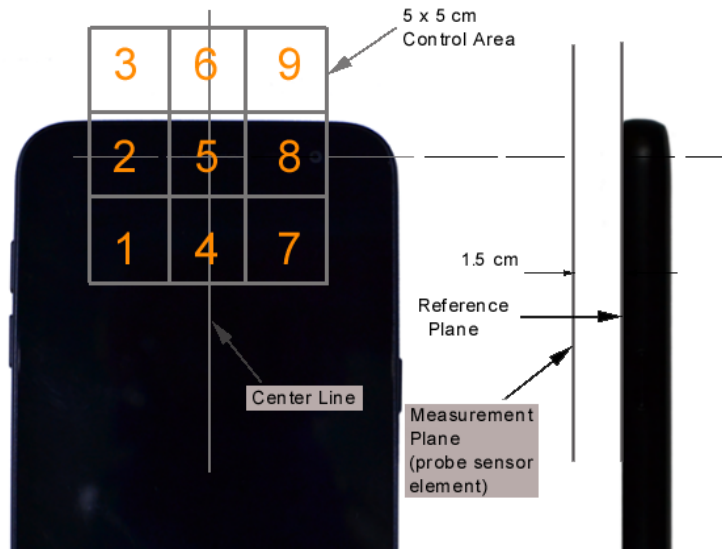


Figure 17-3 5x5 Scan grid above WD

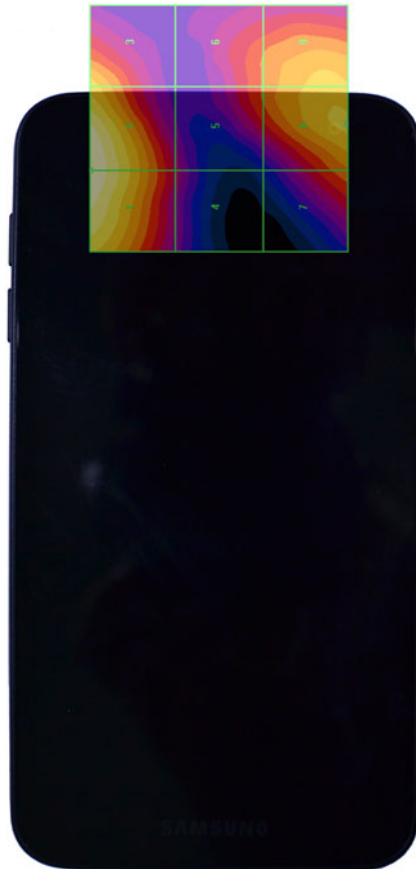




Figure 17-4 E-Field WD Scan overlay

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